

SLOVENSKI STANDARD oSIST prEN IEC 63489:2024

01-september-2024

Zbirka podatkov – Skupni koncepti podatkov za pametno proizvodnjo

Db - Common data concepts for smart manufacturing

Base de données - Concepts de données communs pour la fabrication intelligente

Ta slovenski standard je istoveten z: prEN IEC 63489:2024

ocument Proview

<u>ICS:</u>

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25.040.01 A Sistemi za avtomatizacijo v 4 Industrial automation 29e6/osist-pren-iec-63489-2024 systems in general
 35.240.50 Uporabniške rešitve IT v industriji

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65E/1084/CDV

COMMITTEE DRAFT FOR VOTE (CDV)

PROJECT NUMBER:	
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65E/928/NP, 65E/991/RVN	

IEC SC 65E : DEVICES AND INTEGRATION IN ENTERPRISE SYSTEMS SECRETARIAT: SECRETARY: United States of America Mr David Richmond OF INTEREST TO THE FOLLOWING COMMITTEES: PROPOSED HORIZONTAL STANDARD SC 3D,TC 65,TC 121 Other TC/SCs are requested to indicate their interest, if any, in this CDV to the secretary. FUNCTIONS CONCERNED: **EMC ENVIRONMENT** QUALITY ASSURANCE SAFETY SUBMITTED FOR CENELEC PARALLEL VOTING **NOT SUBMITTED FOR CENELEC PARALLEL VOTING** Attention IEC-CENELEC parallel voting The attention of IEC National Committees, members of CENELEC, is drawn to the fact that this Committee Draft for Vote (CDV) is submitted for parallel voting. The CENELEC members are invited to vote through the CENELEC online voting system.

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TITLE:

DB - Common data concepts for smart manufacturing

PROPOSED STABILITY DATE: 2029

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Full information on the voting for its approval can be found in the report on voting indicated in 66 the above table. 67

The language used for the development of this International Standard is English. 68

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